

| | | | | |
|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/593,630 | | Applicant(s)/Patent Under Reexamination IDE ET AL. | |
| | Examiner JOSE M. DIAZ | | Art Unit 2879 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-2004/0104672 A1 | 06-2004 | Shiang et al. | 313/506 |
| * | B | US-2005/0051791 A1 | 03-2005 | Gotoh et al. | 257/099 |
| * | C | US-2005/0233156 A1 | 10-2005 | Senzaki et al. | 428/446 |
| * | D | US-2006/0097630 A1 | 05-2006 | Shiokawa et al. | 313/504 |
| * | E | US-2007/0099024 A1 | 05-2007 | Nii et al. | 428/690 |
| * | F | US-2009/0153030 A1 | 06-2009 | Huo et al. | 313/504 |
| * | G | US-2011/0284893 A1 | 11-2011 | Hoeppe et al. | 257/98 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|-----------------|---------------|----------------|
| | N | WO 2004095892 A1 | 11-2004 | World Intellect | KUMA, HITOSHI | H05B 33/26 |
| | O | WO 2005029923 A1 | 03-2005 | World Intellect | NII et al. | H05B 33/14 |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | I | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.